 Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/629,634	IWAI ET AL.
Examiner	Art Unit
TUAN A. PHAM	2618

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	575.1	9/1/2006	РНАМ
	575.5		
	575.6		
	575.7		
	97	9/1/2006	PHAM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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		DATE	EXMR
Consulted with: Duc nguyen	g)/1/2006	РНАМ
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